

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/014,823 DE JONG ET AL.	
		Examiner	Art Unit William C. Vaughn, Jr.	2143 Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,774,668	06-1998	Choquier et al.	709/223
	B	US-2002/0059425	05-2002	Belfiore et al.	709/226
	C	US-2005/0022001	01-2005	Bahl et al.	713/200
	D	US-2002/0184507	12-2002	Makower et al.	713/182
	E	US-2002/0124116	09-2002	Yaung, Alan T.	709/313
	F	US-5,706,427	01-1998	Tabuki, Takaaki	713/201
	G	US-5,202,921	04-1993	Herzberg et al.	713/162
	H	US-2002/0144119	10-2002	Benantar, Messaoud	713/171
	I	US-2002/0199004	12-2002	Jaye, Daniel J.	709/228
	J	US-2001/0051996	12-2001	Cooper et al.	709/217
	K	US-2003/0065947	04-2003	Song et al.	713/201
	L	US-2003/0014631	01-2003	Sprague, Steven	713/168
	M	US-2003/0028773	02-2003	McGarvey et al.	713/176

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.